

Features

- CRM G4 SiC MOSFET Technology
- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Avalanche Ruggedness
- Fast Reverse Recovery
- AEC-Q101 Qualified

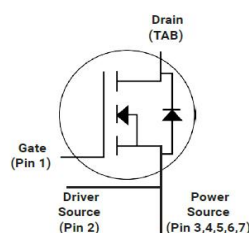
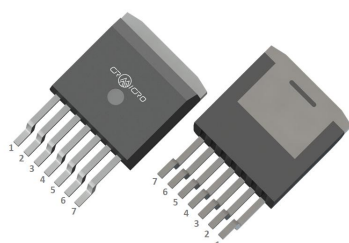
Applications

- Solar Inverters
- High Voltage DC/DC Converters
- On Board Charger(OBC)
- EV Charger

Product Summary

V _{DS}	1200V
R _{DS(on)_typ}	35m Ω
I _D	55A

100% Avalanche Tested



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Qty
CRXSP35M120G4Q	X35M120G4Q	TO-263-7	Reel	800pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	1200	V
Continuous drain current V _{GS} =18V, T _C = 25°C V _{GS} =18V, T _C = 100°C	I _D	55 39	A
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _{D(pulse)}	138	A
Avalanche energy, single pulse (L=10mH, R _g =25 Ω)	E _{AS}	723	mJ
Gate-Source voltage (dynamic) ^{a1}	V _{GSmax}	-10/+22	V
Gate-Source voltage (static) ^{a2}	V _{GSop}	-5/+18	V
Power dissipation (T _C =25°C, T _J =175°C)	P _D	208	W
Operating Junction and Storage Temperature	T _j , T _{stg}	-55...175	°C

a1: When using MOSFET Body Diode V_{GSmax} = -5V/+22V

a2: MOSFET can also safely operate at 0/+18V

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	0.72	°C/W
Thermal resistance, junction – ambient. Max	R_{thJA}	50	

Electrical Characteristic (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	$V_{(BR)DSS}$	1200	-	-	V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	2	-	4	V	$V_{DS}=V_{GS}, I_D=10mA$
Zero gate voltage drain current	I_{DSS}	-	0.1	100	μA	$V_{DS}=1200V, V_{GS}=0V$ $T_j=25^\circ\text{C}$
		-	10	-		$T_j=175^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	-	± 100	nA	$V_{GS}=-10/+22V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	45	56	mΩ	$V_{GS}=15V, I_D=22A,$ $T_j=25^\circ\text{C}$
		-	69	-		$T_j=175^\circ\text{C}$
Drain-source on-state resistance	$R_{DS(on)}$	-	35	46	mΩ	$V_{GS}=18V, I_D=22A,$ $T_j=25^\circ\text{C}$
		-	65	-		$T_j=175^\circ\text{C}$
Transconductance	g_{fs}	-	18	-	S	$V_{DS}=20V, I_{DS}=22A$

Dynamic Characteristic

Internal Gate resistance	R _{G(int)}	-	3.2	-	Ω	f=1MHz
Input Capacitance	C _{iss}	-	1826	-	pF	V _{GS} =0V, V _{DS} =1000V, f=1MHz
Output Capacitance	C _{oss}	-	72.8	-		
Reverse Transfer Capacitance	C _{rss}	-	4	-		
Coss Stored Energy	E _{oss}	-	45.7	-	μJ	
Gate Total Charge	Q _g	-	79.6	-	nC	VGS=-5/18V VDS=800V ID=22A
Gate-Source charge	Q _{gs}	-	26.9	-		
Gate-Drain charge	Q _{gd}	-	21.3	-		
Turn-on delay time	t _{d(on)}	-	9	-	ns	VDD=800V,ID=22A VGS=-5V/18V, RG=2.5Ω, L=120uH
Rise time	t _r	-	12.8	-		
Turn-off delay time	t _{d(off)}	-	21.8	-		
Fall time	t _f	-	11.2	-		
Turn-On Switching Energy	E _(on)	-	93	-	μJ	
Turn Off Switching Energy	E _(off)	-	84.5	-		

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	4	-	V	$V_{GS}=0V, I_F=11A$
		-	3.5	-	V	$V_{GS}=0V, I_F=11A, T_j=175^\circ C$
Continuous Diode Forward Current	I_S	-	-	55	A	$V_{GS}=0V$
Diode pulse Current	$I_{S,pulse}$	-	-	138	A	pulse width t_p limited by T_{jmax}
Body Diode Reverse Recovery Time	t_{rr}	-	16	-	ns	$di/dt=1000A/us$ $I_F=22A$ $V_{dd}=800V$ $T_j=25^\circ C$
Body Diode Reverse Recovery Charge	Q_{rr}	-	140	-	nC	
Body Diode Peak Reverse Recovery Current	I_{rrm}	-	14.8	-	A	
Body Diode Reverse Recovery Time	t_{rr}	-	40.6	-	ns	$di/dt=1000A/us$ $I_F=22A$ $V_{dd}=800V, T_j=175^\circ C$
Body Diode Reverse Recovery Charge	Q_{rr}	-	280	-	nC	
Body Diode Peak Reverse Recovery Current	I_{rrm}	-	14.8	-	A	

Typical Performance Characteristics

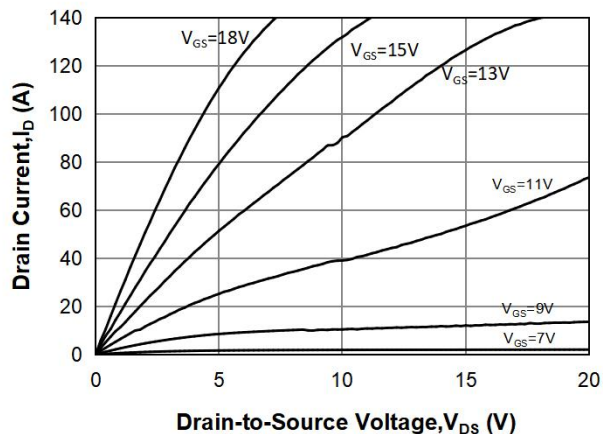
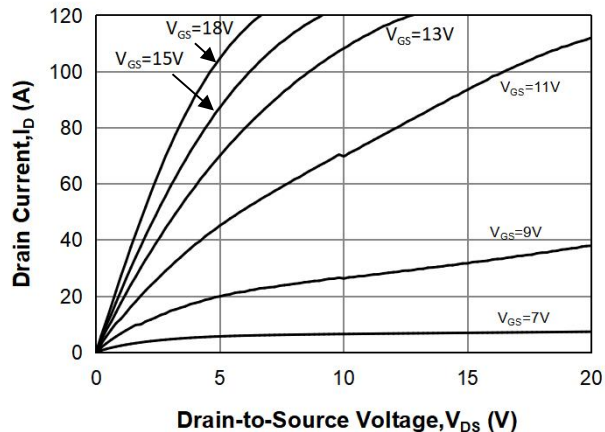
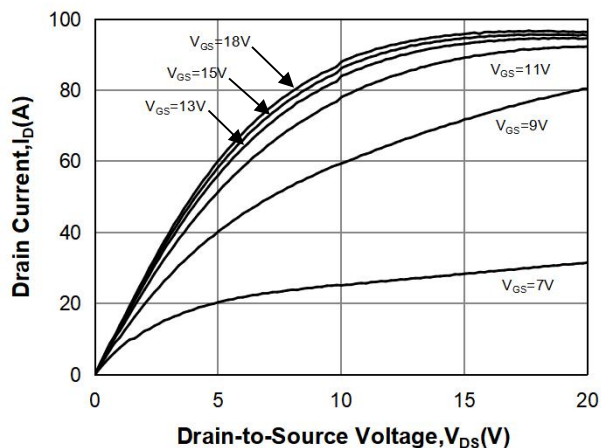
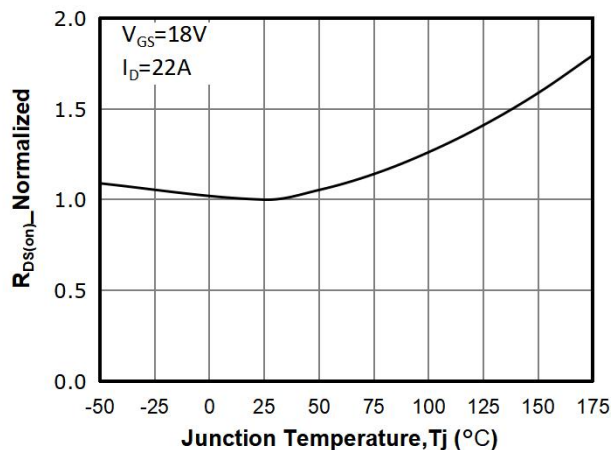
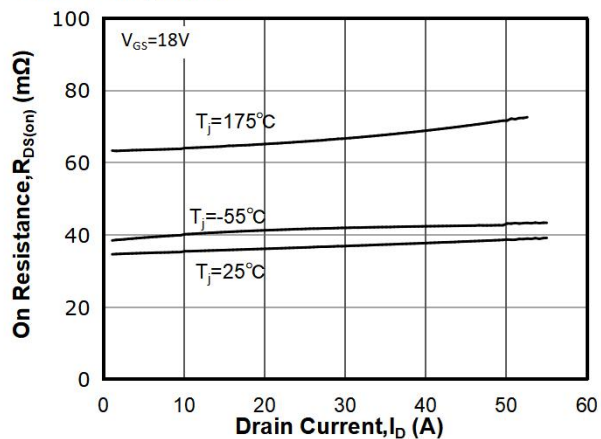
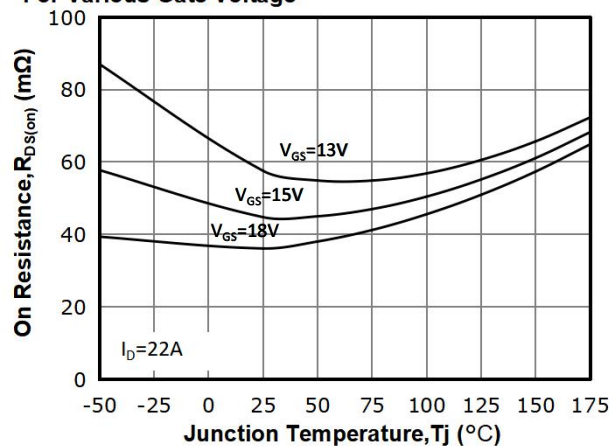
Fig 1. Output Characteristics ($T_J = -55^\circ\text{C}$)

Fig 2. Output Characteristics ($T_J = 25^\circ\text{C}$)

Fig 3. Output Characteristics ($T_J = 175^\circ\text{C}$)

Fig 4: $R_{DS(on)}$ vs. Temperature

Fig 5: On-Resistance vs. Drain Current For Various Temperatures

Fig 6: $R_{DS(on)}$ vs. Temperature For Various Gate Voltage


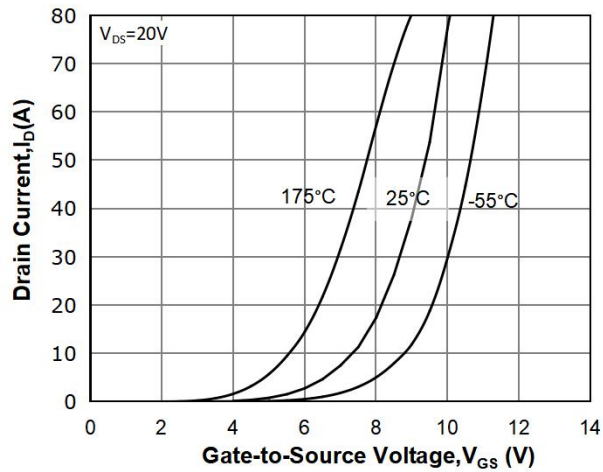
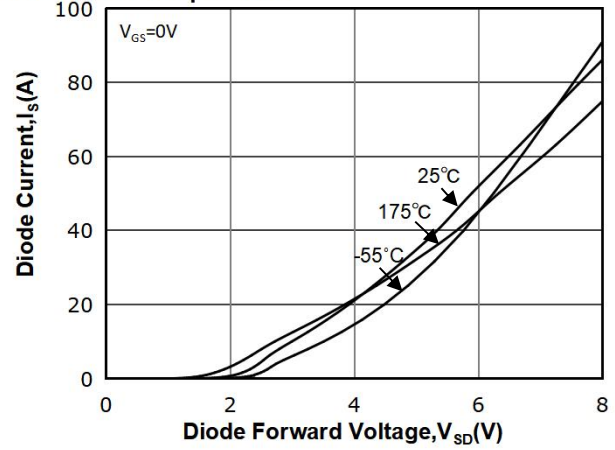
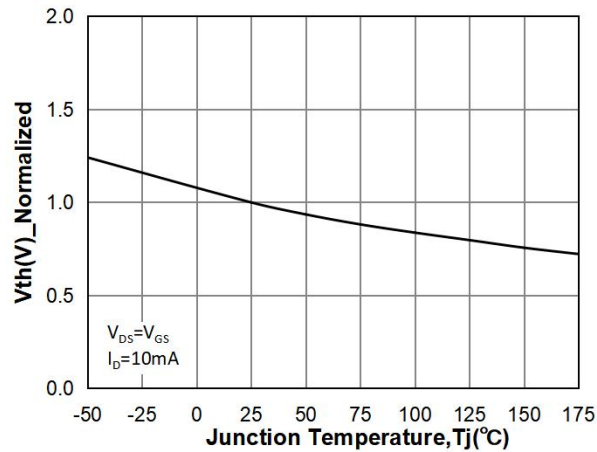
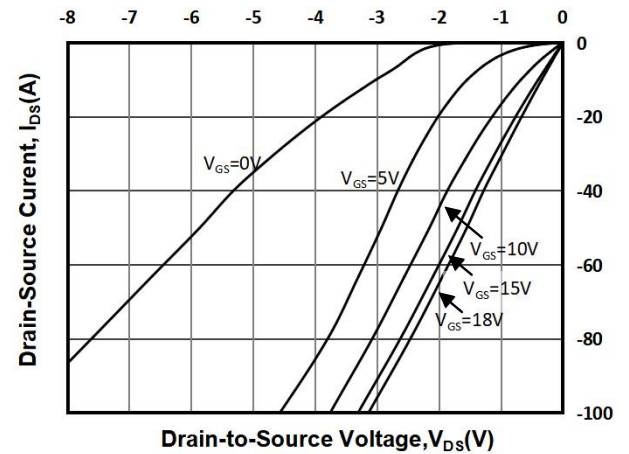
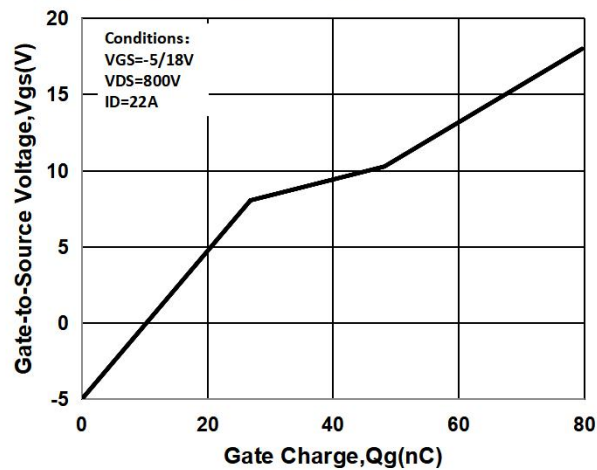
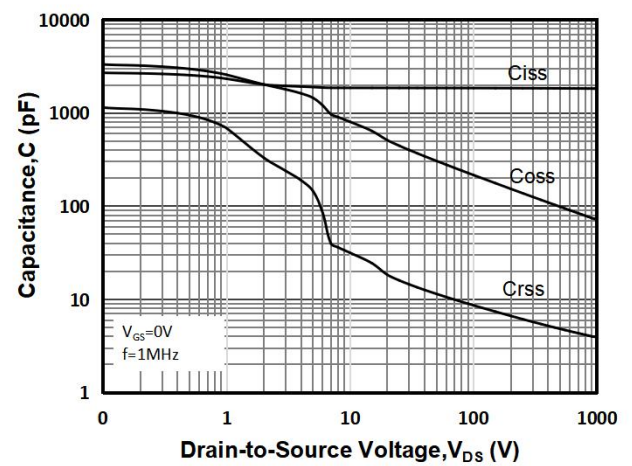
Fig 7: Transfer Characteristics

Fig 8: Body-diode Forward Characteristics For Various Temperatures

Fig 9: V_GS(th) Vs T_J Characteristics

Fig 10: 3rd Quadrant Characteristic at 25°C

Fig 11: Gate Charge Characteristics

Fig 12: Capacitance Characteristics


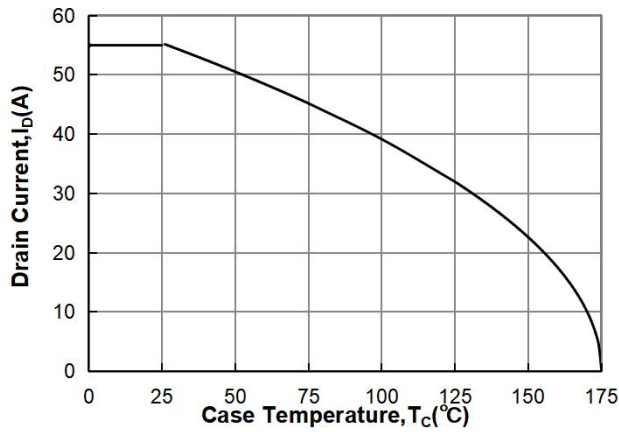
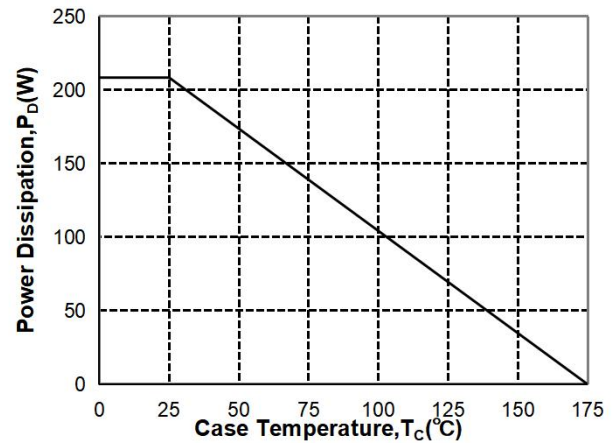
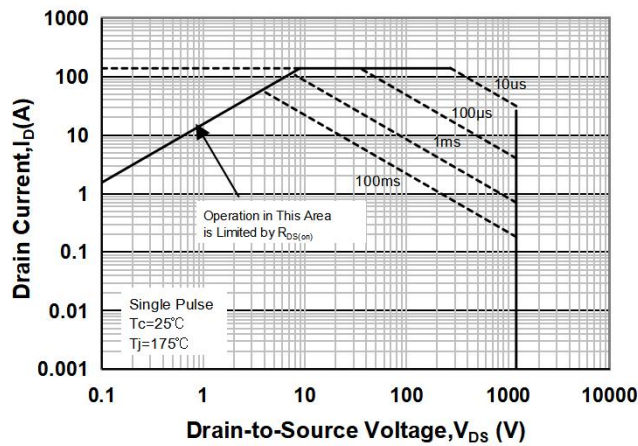
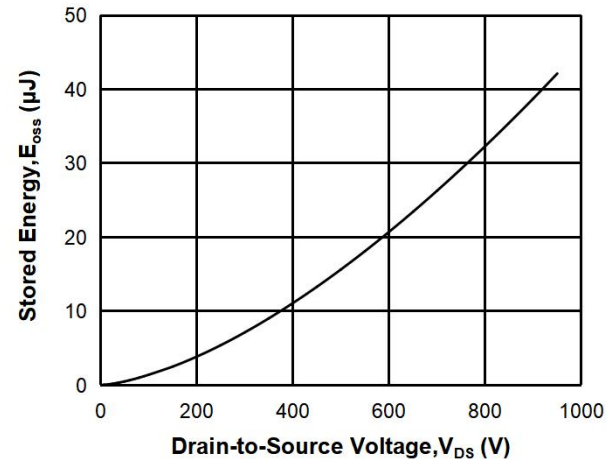
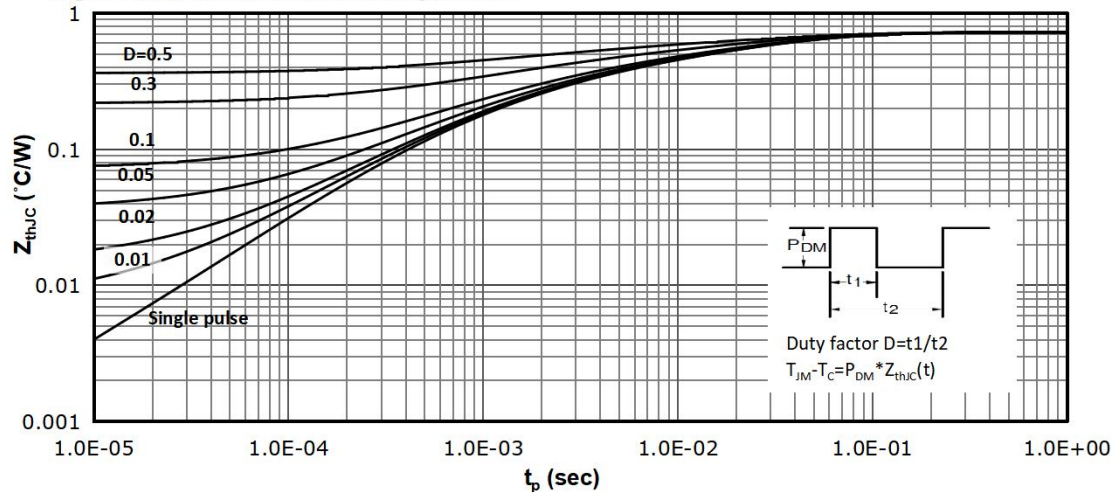
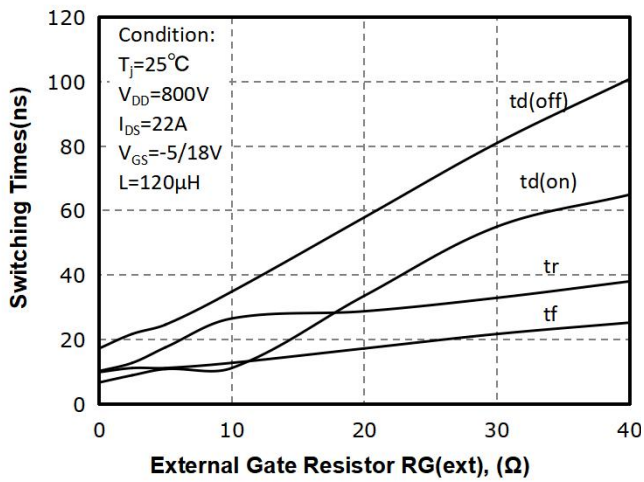
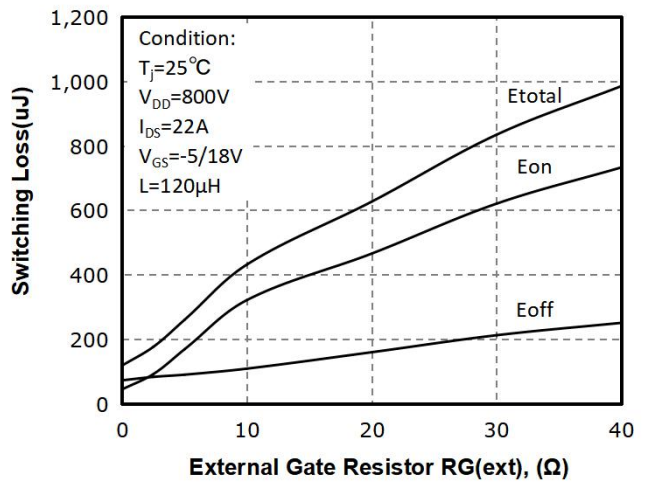
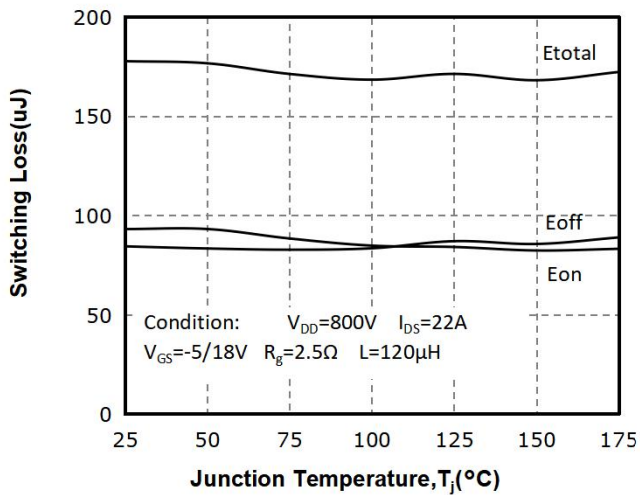
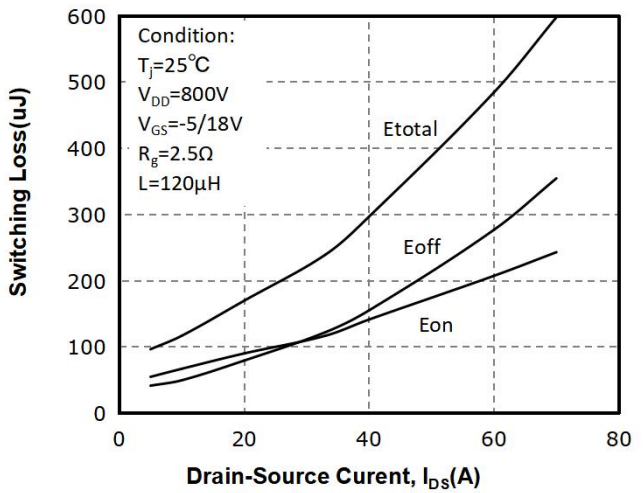
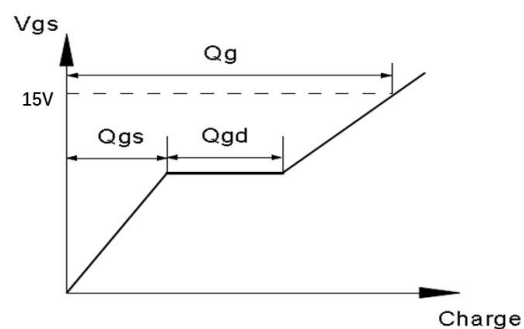
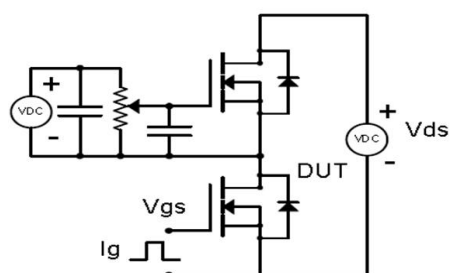
Fig 13: Continuous Drain Current vs. Case Temperature

Fig 14: Maximum Power Dissipation vs. Case Temperature

Fig 15: Safe Operating Area

Fig 16: Output Capacitor Stored Energy

Fig 17: Max. Transient Thermal Impedance


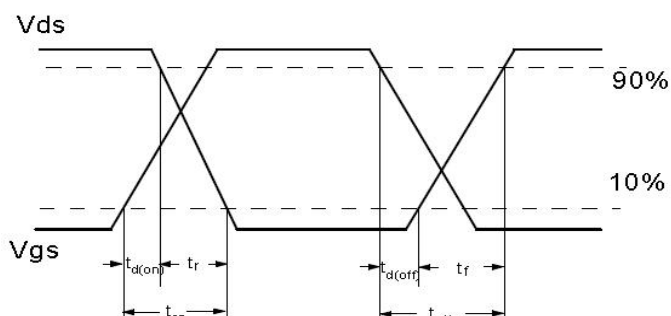
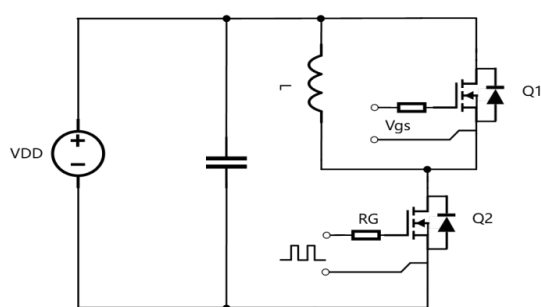
Fig 18: $R_g(\Omega)$ vs. Switching Times(us)

Fig 19: $R_g(\Omega)$ vs. Switching Loss(uJ)

Fig 20: Temperature($^\circ\text{C}$) vs. Switching Loss(uJ)

Fig 21: $I_{DS}(\text{A})$ vs. Switching Loss(uJ)


Test Circuit & Waveform

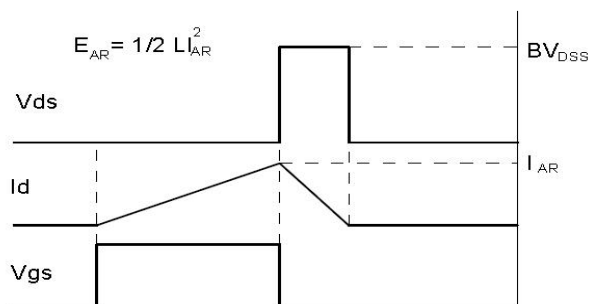
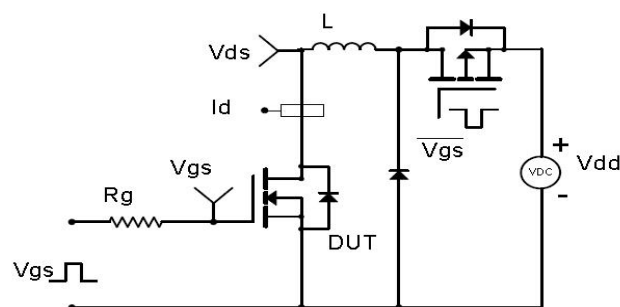
Gate Charge Test Circuit & Waveform



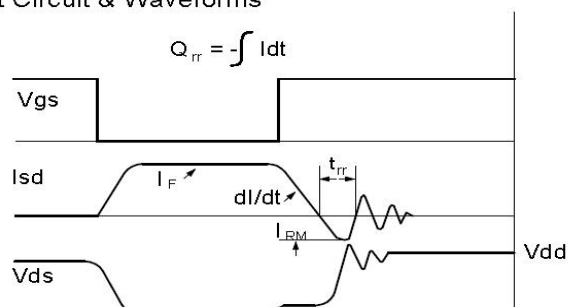
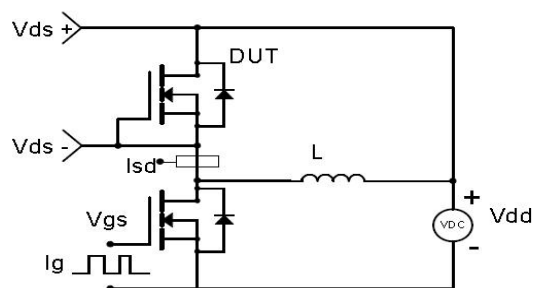
Resistive Switching Test Circuit & Waveforms

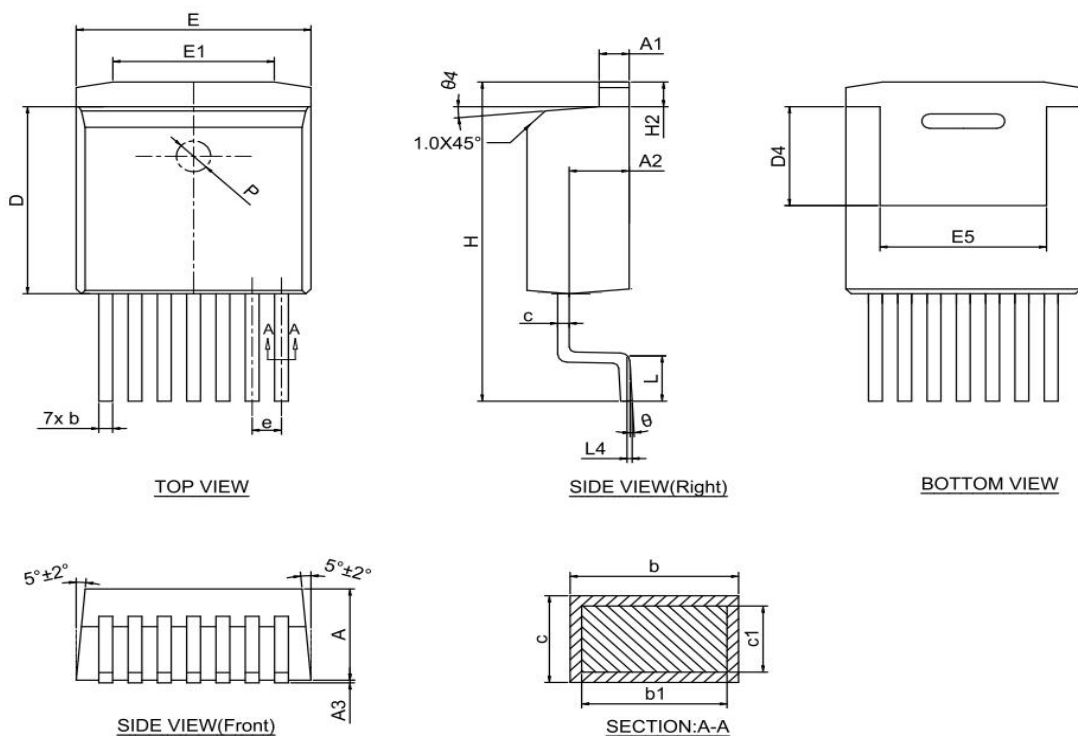


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-263-7


Items	Values(mm)	
	MIN	MAX
A	4.2	4.66
A1	1.15	1.45
A2	2.35	2.85
A3	0	0.3
b	0.5	0.78
b1	0.45	0.75
c	0.49	0.64
c1	0.4	0.6
D	8.83	9.33
D4	4.6	5
e	1.27 BSC.	
E	9.08	10.38
E1	6.4	7.6
E5	6.72	7.72
H	14.9	16.1
H2	0.9	1.45
L	1.8	2.6
L4	0.25 BCS.	
P	1.4	1.6
θ	0°	7°

Revision History

Revision	Date	Major changes
1.0	2025/11/14	Release of formal version
2.0	2026/3/11	Update Ron Spec

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